

Notice of References Cited	Application/Control No. 10/016,701	Applicant(s)/Patent Under Reexamination DAVIES ET AL.	
	Examiner Cynthia Britt	Art Unit 2133	Page 1 of 1

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	C	US-6,081,913	06-2000	Narayanan et al.	714/724
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NON-PATENT DOCUMENTS

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	U	"Delay-Fault Test Generation and Synthesis for Testability Under A Standard Scan Design Methodology" Cheng et al. IEEE Transactions on Computer-Aided Design of Inspec Accession Number: 4567801
	V	"Scan Synthesis for One-Hot Signals" by Mitra et al. International Test Conference Proceedings. 1-6 Nov. 1997 page714 - 72 Inspec Accession Number: 5863303
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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